



PTO/SB/08 Equivalent

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

(Multiple sheets used when necessary) SHEET 1 OF 1	Application No.	10/696,244
	Filing Date	October 28, 2003
	First Named Inventor	Raaijmakers et al.
	Art Unit	2823
	Examiner	Hsien Ming Lee
	Attorney Docket No.	ASMMC.045AUS

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
Lee	1	6,503,330	01-07-2003	Sneh et al.	
Lee	2	6,551,399	04-22-2003	Sneh et al.	
Lee	3	6,613,695	09-02-2003	Pomarede et al.	
Lee	4	US 2004/0121620 A1	06-24-2004	Pomarede et al.	

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>

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Examiner Signature	<i>Hsien Ming Lee</i>	Date Considered	<i>7/6/05</i>
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T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.*paper no. : 050905*

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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
ASMMC.045AUSAPPLICATION NO.  
10/696,244INFORMATION DISCLOSURE STATEMENT  
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(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT  
Raaijmakers et al.FILING DATE  
October 28, 2003GROUP  
~~Unknown~~ 2823

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
<i>Lee</i>	1	6,492,283	12/10/02	Raaijmakers et al.			
<i>Lee</i>	2	6,362,099	03/26/02	Gandikota et al.			
<i>Lee</i>	3	6,482,740	11/19/02	Soininen et al.			

EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
<i>Lee</i>	4	Jennison et al. "Ultrathin Alumina Film Al-Sublattice Structure, Metal Island Nucleation at Terrace Point Defects, and How Hydroxylation Affects Wetting," Faraday Discussion #114, (1999) pp. 45-52.
<i>Lee</i>	5	Kelber et al., "Copper wetting of $\alpha$ -Al <sub>2</sub> O <sub>3</sub> (0001): theory and experiment," Surface Science, 446 (2000) pp. 78-88

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EXAMINER <i>David M. Lee</i>	DATE CONSIDERED <i>7/6/05</i>
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